



An inspection certificate is supplied as standard. Refer to page U-9 for details.

High precision and high performance type surface roughness tester with a dedicated control unit, offering a user-friendly display and simple operation.

- Equipped with a 7.5-inch, color TFT LCD, color icons and touch panel controls, the display unit is easy to read and simple to operate.
- A built-in joystick on the control unit allows quick and easy positioning. The manual adjustment knob allows fine positioning of a small stylus for measuring small holes.
- In addition to the roughness parameters compliant with ISO/JIS/ANSI/VDA surface roughness standards, contour analysis is also available.

SPECIFICATIONS

Model No.	SJ-500	SV-2100M4*1	SV-2100S4*1	SV-2100H4*1	SV-2100W4*1
Stand type	—*2	Manual stand		Motorized stand	
Measuring range	Z1 axis (detector)		800 μm, 80 μm, 8 μm		
	X axis	50 mm	100 mm		
Resolution	X axis		0.05 μm		
	Z1 axis (detector)		0.01 μm (800 μm), 0.001 μm (80 μm), 0.0001 μm (8 μm)		
	Z2 axis (column)	—		1 μm	
Assessed profile		Primary profile, Roughness profile, Waviness profile, DF profile, Roughness motif profile, Waviness motif profile			

*1 While the appearance of the natural stone measuring table varies according to the source, the high stability for which this material is known can always be relied upon.
*2 Stand for **SJ-500** is optional.

Surftest SJ-500/SV-2100 SERIES 178 — Dedicated Control Unit Type Surface Roughness Tester



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A superior data processing tester with PC data analysis for higher efficiency.

Surftest SJ-500P/SV-2100M4 SERIES 178 — Data Processing Unit (PC) Surface Roughness Testers



FORMTRACEPAK: Best-selling Surface Roughness Analysis Program

Best-selling dedicated software for surface roughness measurement and analysis. Features a flexible printer format and creation of an original inspection certificate.

SPECIFICATIONS

Type of data processing unit	PC type	
Model No.	SJ-500P	SV-2100M4*2
Elevating shaft mechanism of stand	—*1	Manual operation only
Measuring range	X axis	100 mm
	Z1 axis (detector)	800 μm, 80 μm, 8 μm
Z2-axis (column) travel range	—	350 mm
Resolution	X axis	0.05 μm
	Z1 axis (detector)	0.01 μm (800 μm), 0.001 μm (80 μm), 0.0001 μm (8 μm)
	Z2 axis (column)	—
Applicable standards	JIS 1982/JIS 1994/JIS 2001/ISO 1997/ANSI/VDA	
Assessed profile	Primary profile, Roughness profile, Waviness profile, Filtered waviness profile, Rolling circle waviness profile, Rolling circle center line waviness profile, Envelope residual profile, DIN4776 profile, Roughness motif profile, Waviness motif profile	

*1 The simplified stand or manual column stand is available as an optional accessory.

*2 While the appearance of the natural stone measuring table varies according to the source, the high stability for which this material is known can always be relied upon.



Refer to the Surftest **SJ-500/SV-2100** Brochure (**E15006**) for more details.